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diamond



Engineering and Physical Sciences  
Research Council



University  
of Glasgow | Experimental  
Particle Physics

# Measurements of 3D Detectors

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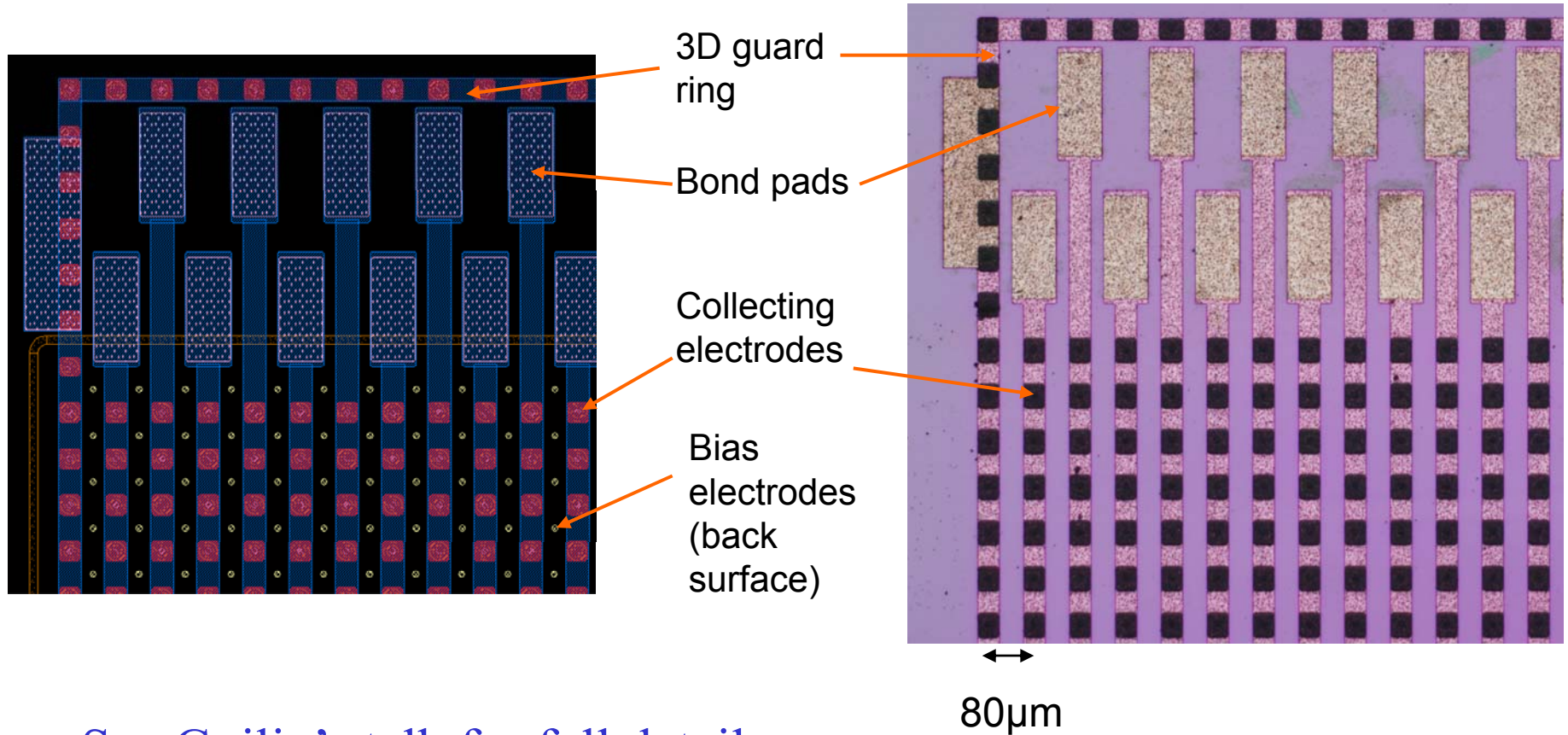
Diamond Synchrotron

RD50 Workshop, June 2008

# 3D Devices

Devices include: Pads, strips, pixels detectors, test structures

## Typical device layout – Strip detector, 80 $\mu$ m pitch



•See Giulio's talk for full details

# Wafers

Two 4" wafers produced  
one used for the electrical tests

other for bumpbonding

## Pixel:

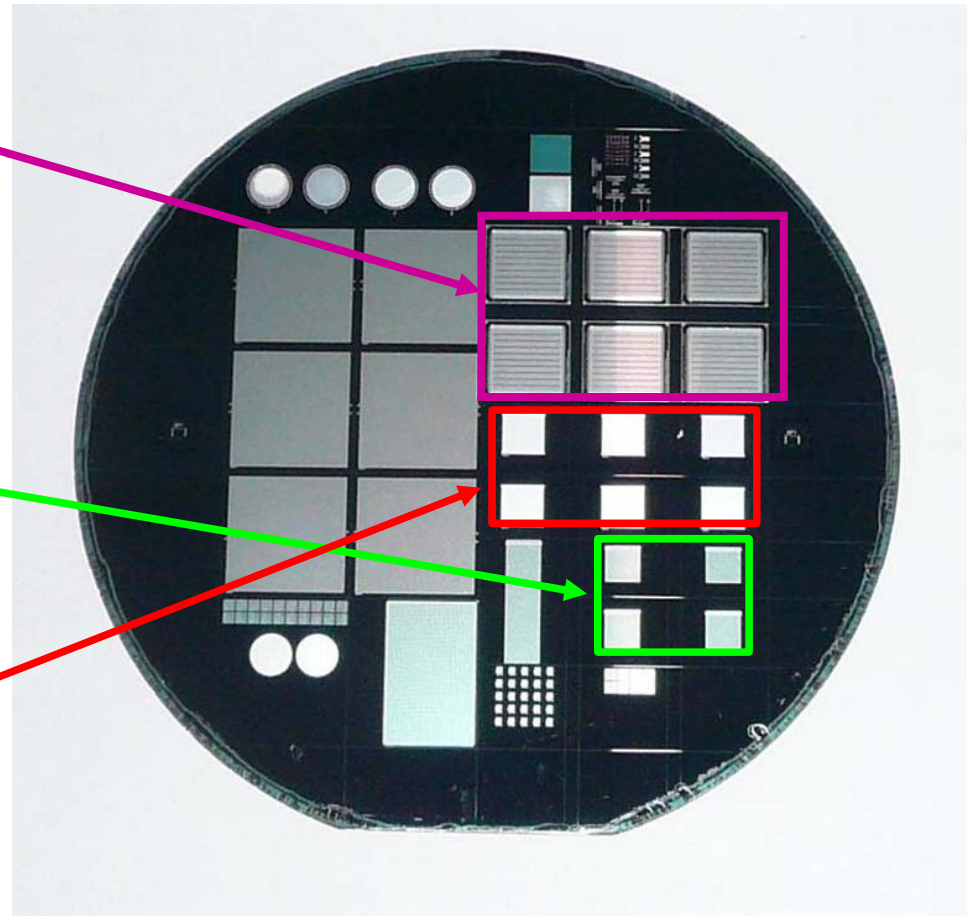
- 6 Medipix2
- 6 ATLAS pixels
- 1 Pilatus

## Strips:

- 4 short strips
- 1 long strip

## -Other:

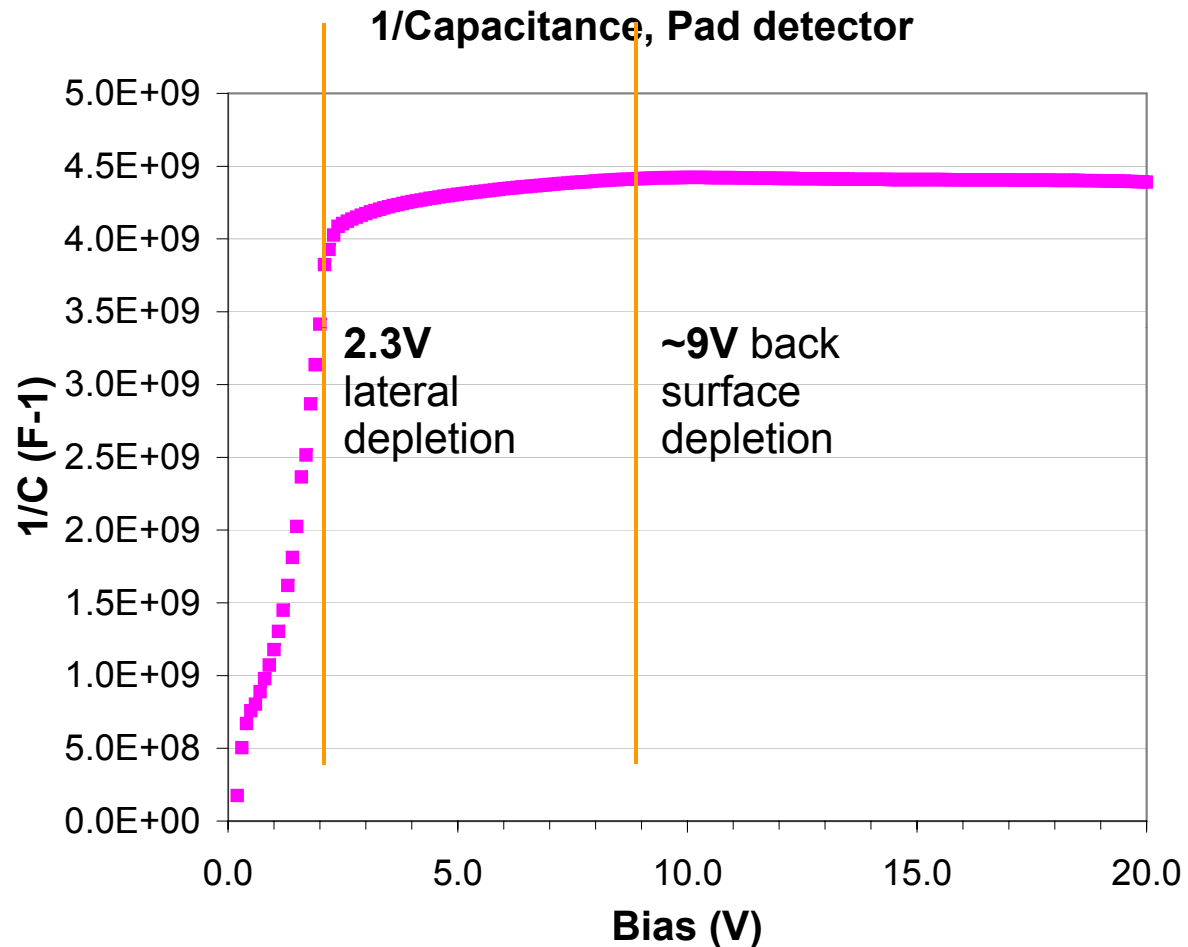
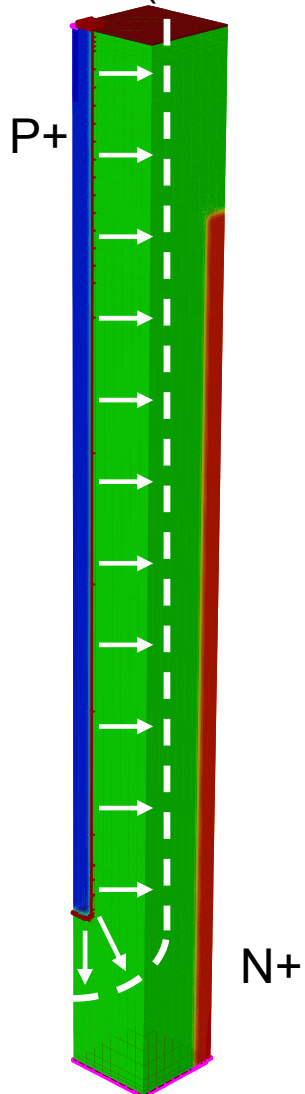
- 6 pad diodes
- Test structures



Lateral depletion around column (~2V in sim.)

# Pre-Irradiation Pads CV

- Pad detector – 90 \* 90 columns, 55μm pitch

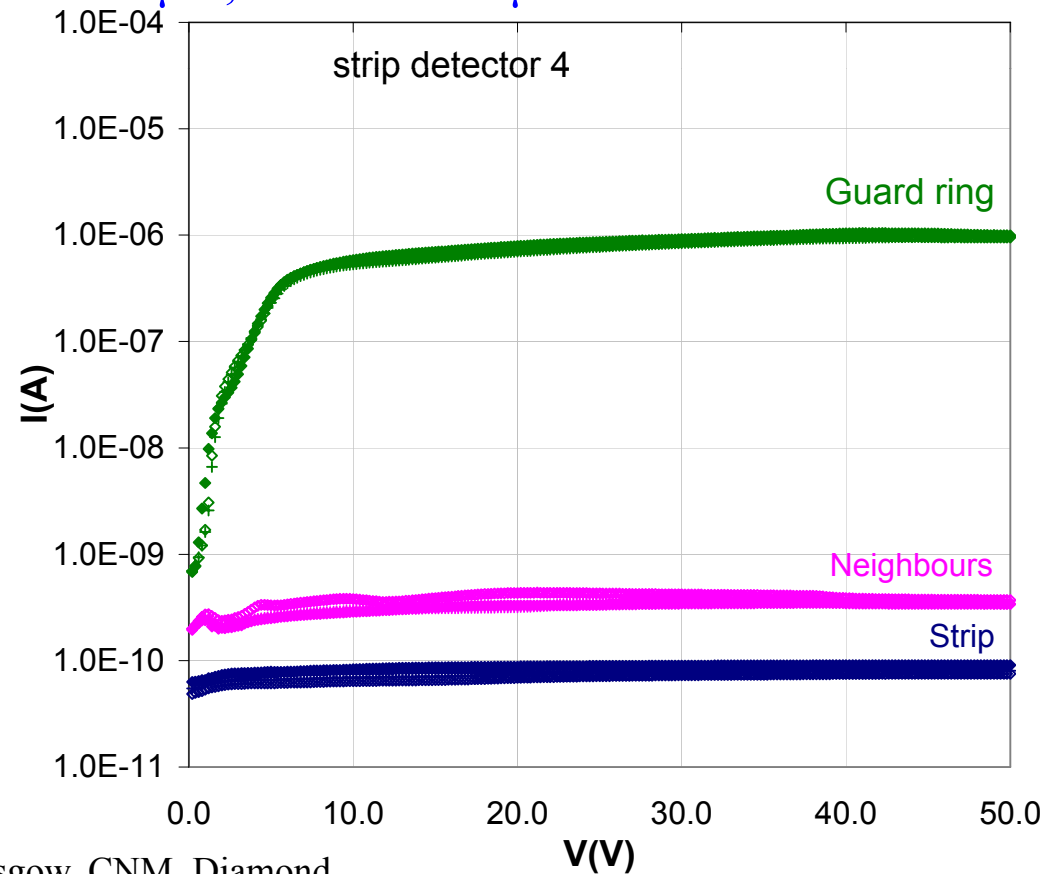
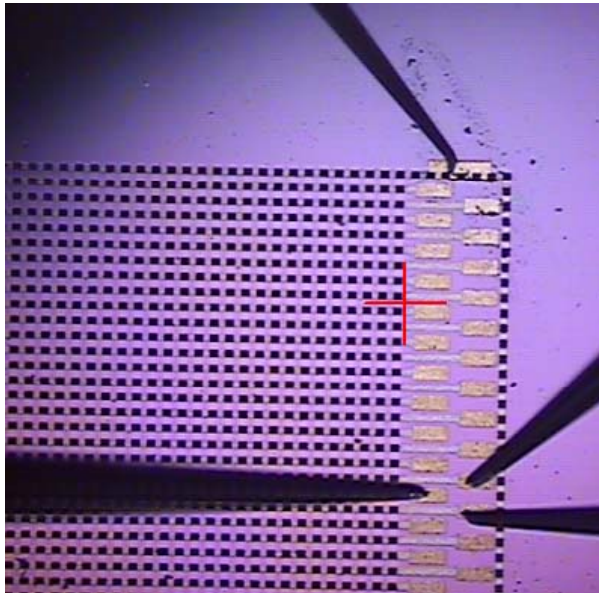


Depletion to back surface from tip of column (~8V in sim.)

- No breakdown observed, one device 200V

# Pre-irradiation Strip IV

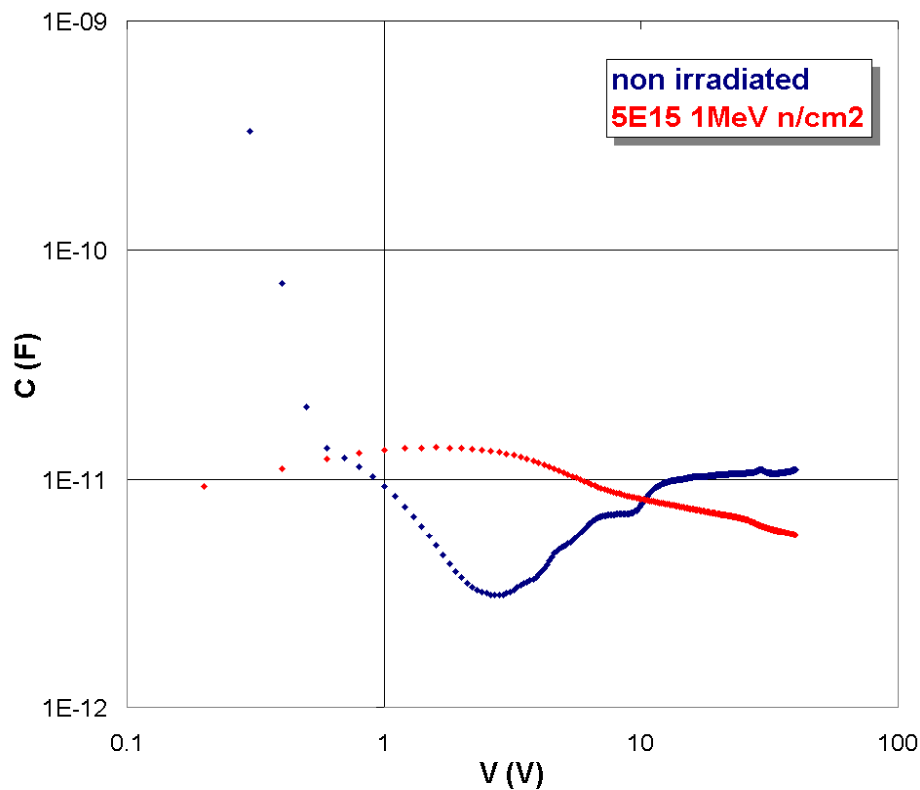
- Measured with 3 strips and guard ring at 0V, backside biased
- Strip currents  $\sim 100$  pA ( $T = 21^\circ\text{C}$ ) in all 4 detectors (2 pA/hole)
- Can reliably bias detectors to 50 V (20 times lateral depletion voltage)
- Capacitance to backplane 10 pF/strip
- Guard ring currents vary: highest 20  $\mu\text{A}$ , lowest 0.03  $\mu\text{A}$  at 10V





# Irradiated Strip CV

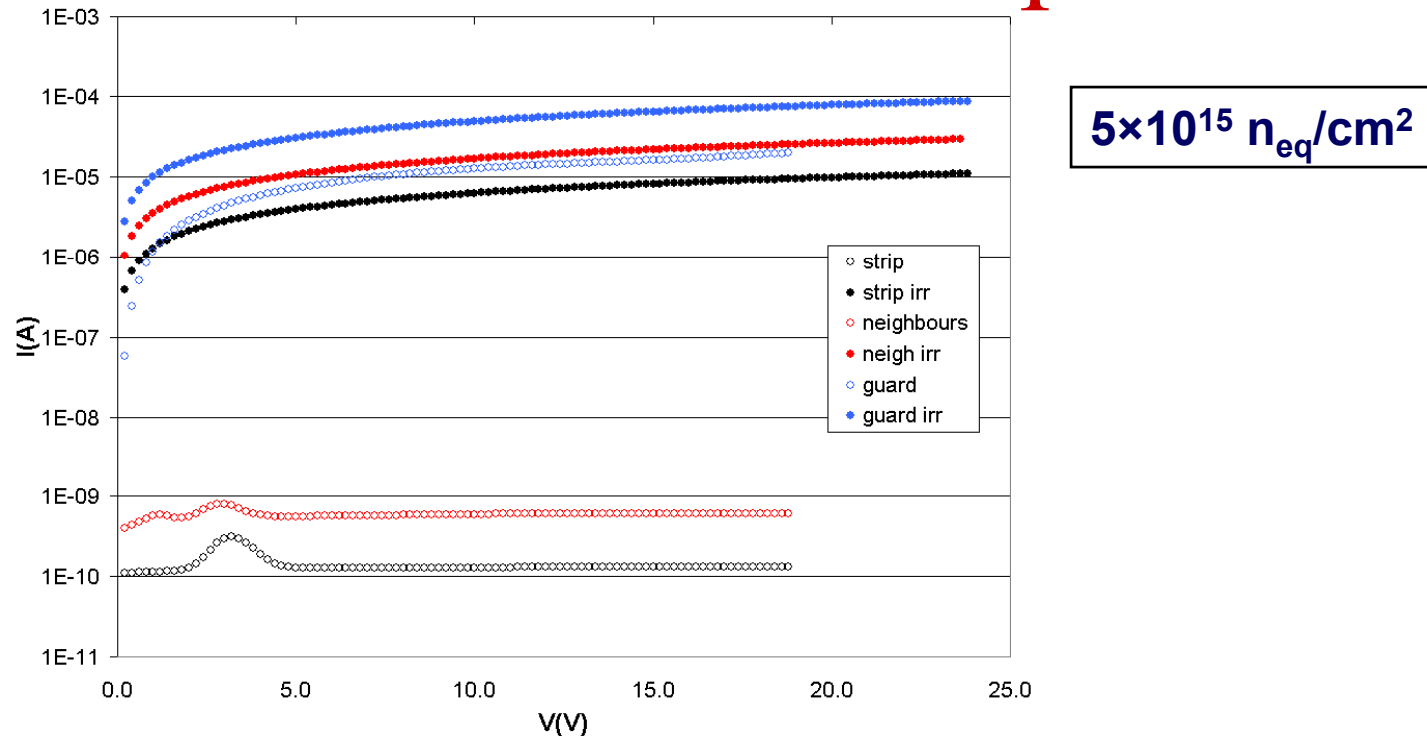
Irradiation and dosimetry: Ljubljana  $5 \times 10^{15} \text{ n}_{\text{eq}}/\text{cm}^2$   
Detectors not annealed, kept at  $-13^\circ\text{C}$



$C$  measured between strip and backplane,  $21^\circ\text{C}$ :

- Non-irradiated:  $C$  stable after  $10\text{ V}$
- Irradiated: Substrate not fully depleted at  $40\text{ V}$

# Irradiated Strip IV



- Same setup as non-irradiated characterisation, 21°C
- Currents too high to bias to full depletion
- Simulation:  $V(\text{lat. depletion}) = \sim 50V$ 
  - $I(50V) \sim 20 \mu A/\text{strip}$  at 20°C
- Reasonable current damage constant,  $\alpha \sim 6 \times 10^{-17} \text{ A/cm}$

# MIP test setup - LHCb Velo

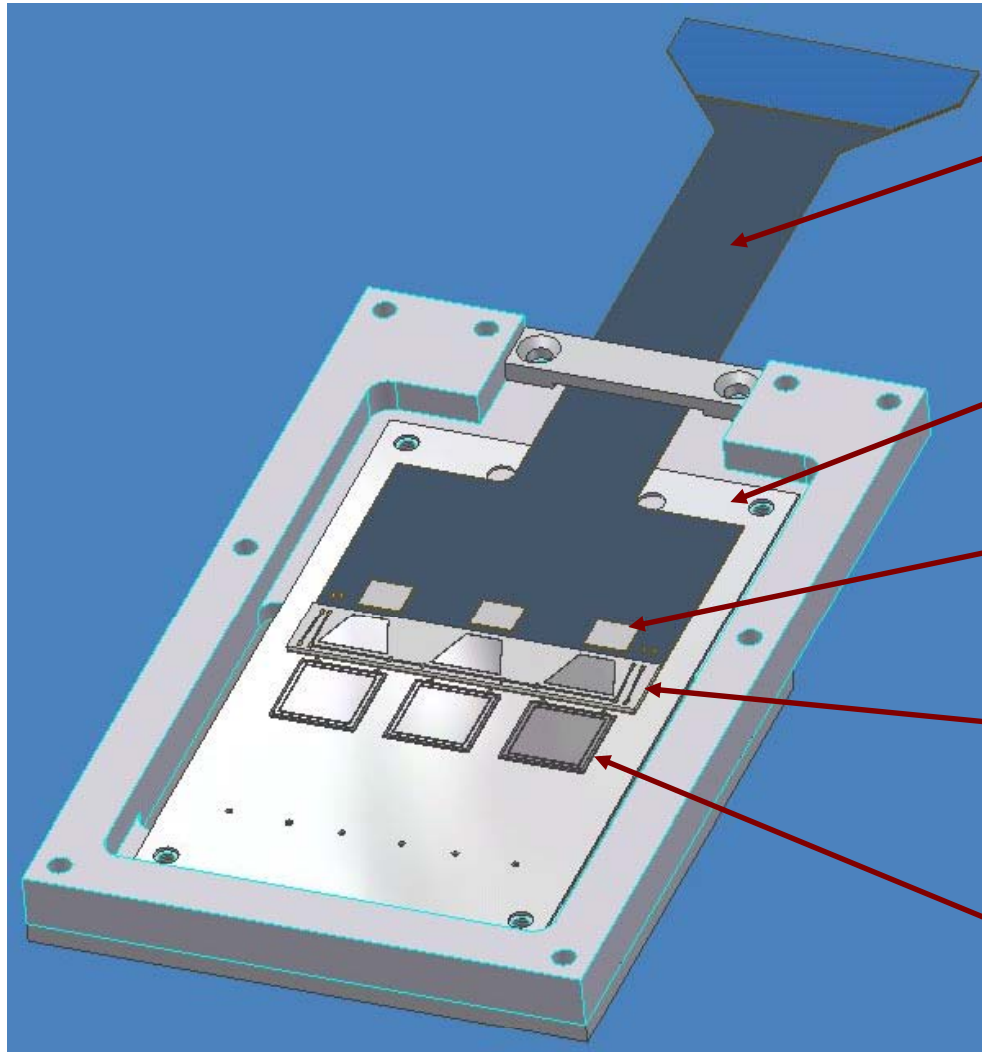
- Stand-alone setup
- Sr90 source and scintillator / PMT trigger
- Beetle strip readout chip (128 channels)
  - Positive or negative polarity
  - Analogue, 25ns
- Logic only accepts triggers arriving at a specific time relative to the sampling clock
  - Ensures sampling at peak of pulse
  - Allows measurement of front-end pulse shape
- TELL1 readout board reads out up to 4 modules
  - ADC conversion of data
  - Controls Beetle settings, test pulses etc.
- Software decodes and processes data
  - Pedestal subtraction, FIR Filter, linear common-mode subtraction, clustering



(See L. Eklund's talk at the 11<sup>th</sup> RD50 Workshop)



# Modules



**Pre-production hybrids from LHCb Inner Tracker**

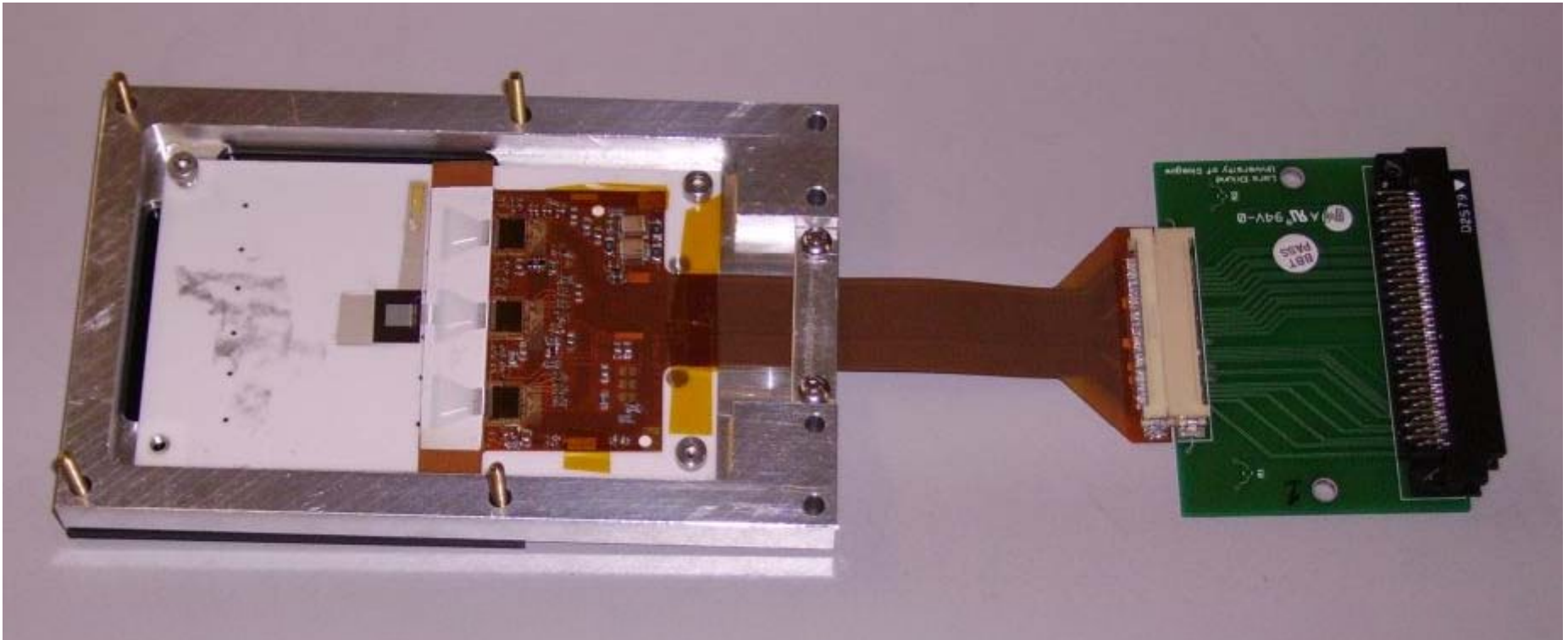
**Alumina baseboards (96% Al<sub>2</sub>O<sub>3</sub>, Coors Tek)**

**Beetle chips**

**Pitch Adaptors (produced in Glasgow)**

**Sensors**

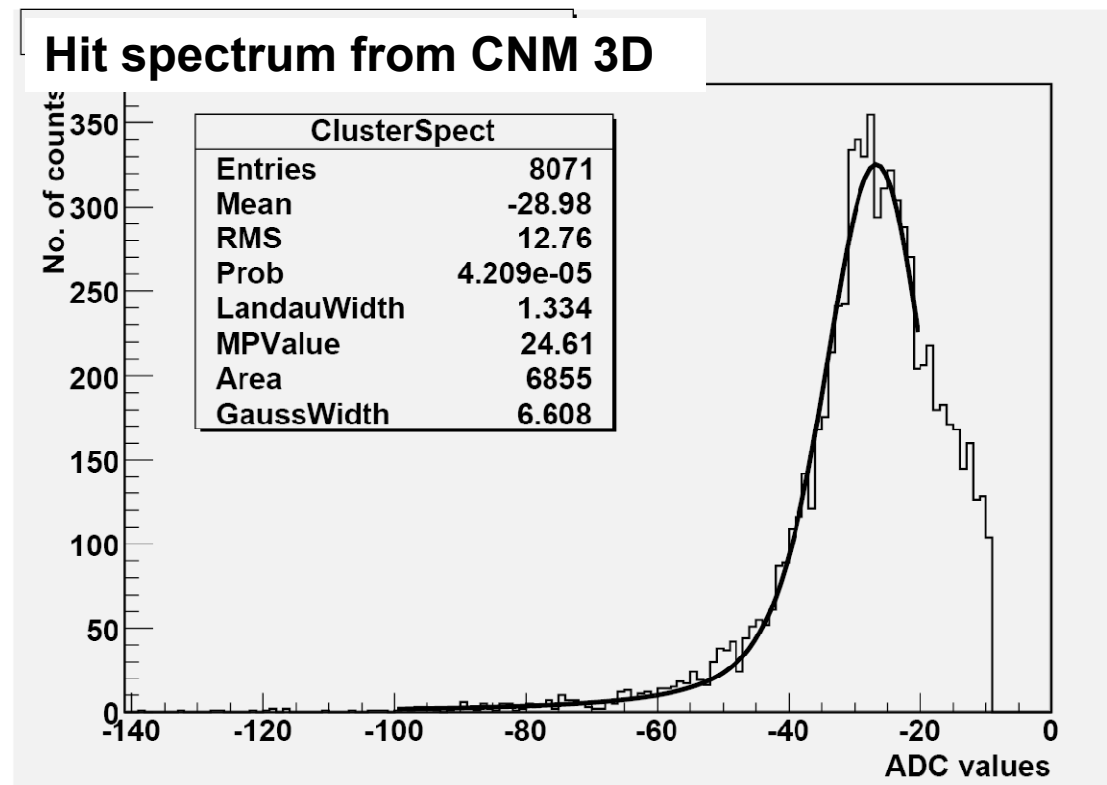
# 3D detector module



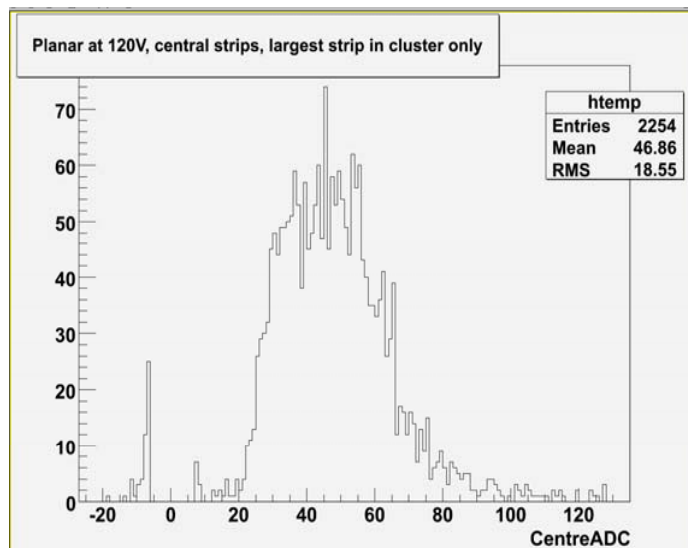
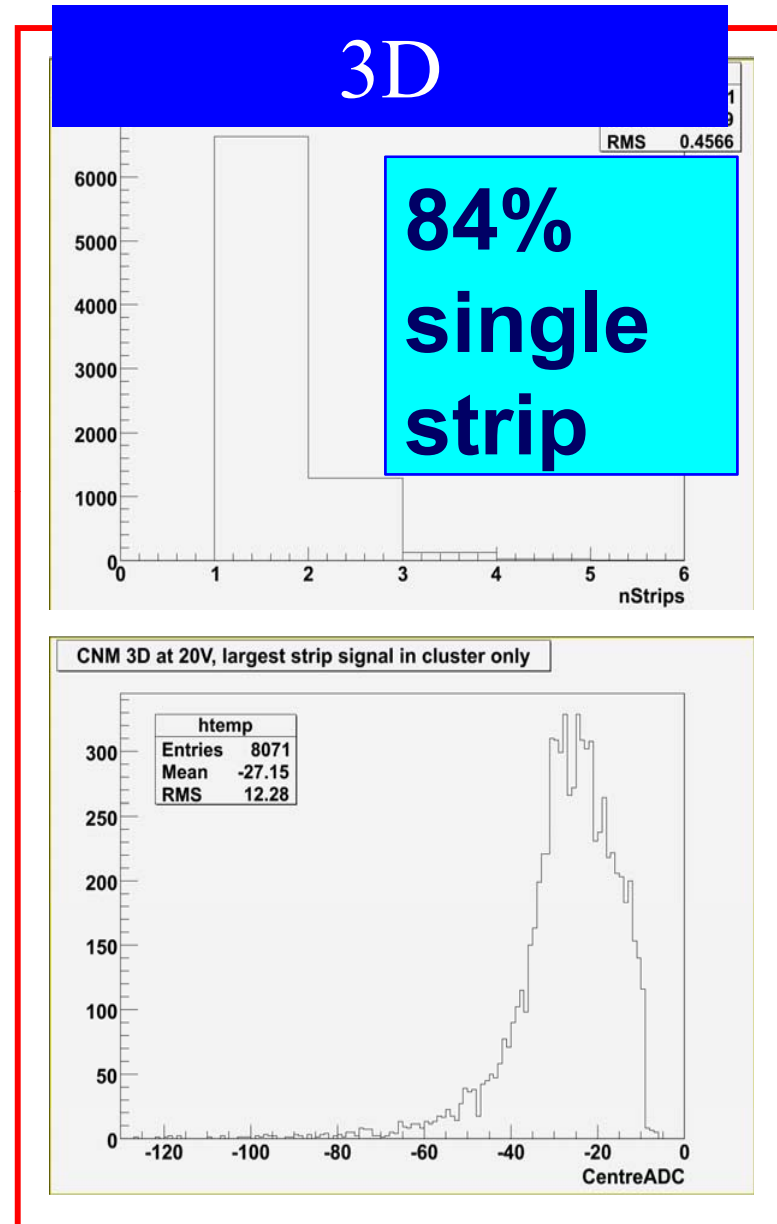
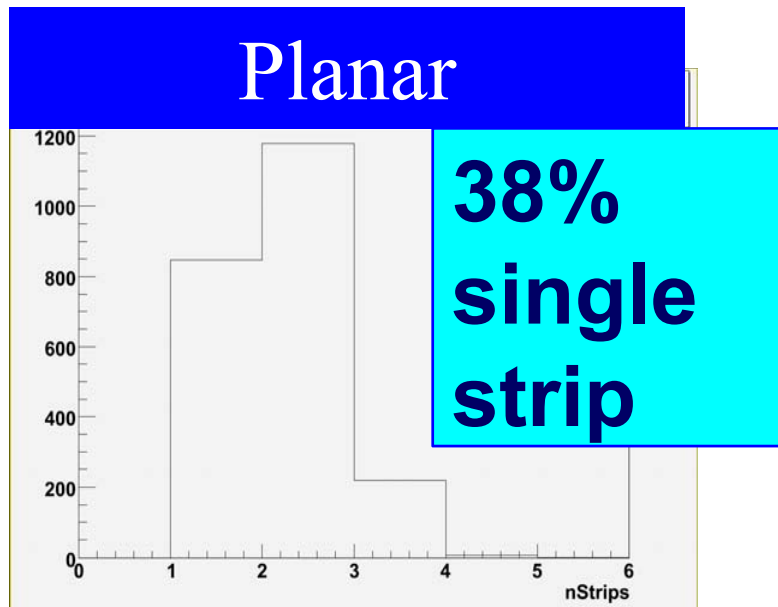
- Strip detectors DC coupled
- Unirradiated ( $I=100$  pA) direct to FE chip
- Irradiated AC coupling needed → RC filter
  - No irradi. MIP results today

# Non-irradiated Strip MIP

- Fitted with Landau convoluted with Gaussian
- More low-amplitude hits seen than expected from Landau
  - Possibly due to particles passing through columns?
- Most probable value
  - 24.6 ADC counts
- Typical noise
  - 1.75 ADC counts
- Signal/noise
  - 15:1



# Cluster Size: Planar vs 3D



- Careful study as sensitive to data processing (cluster thresholds, FIR filter)

# 3D Pixel Medipix2

- 3 Medipix3D (+ 1 planar) bump bonded at VTT
- USB Interface for Medipix (CTU, Prague)
- Tested with X-ray source Glasgow, Diamond

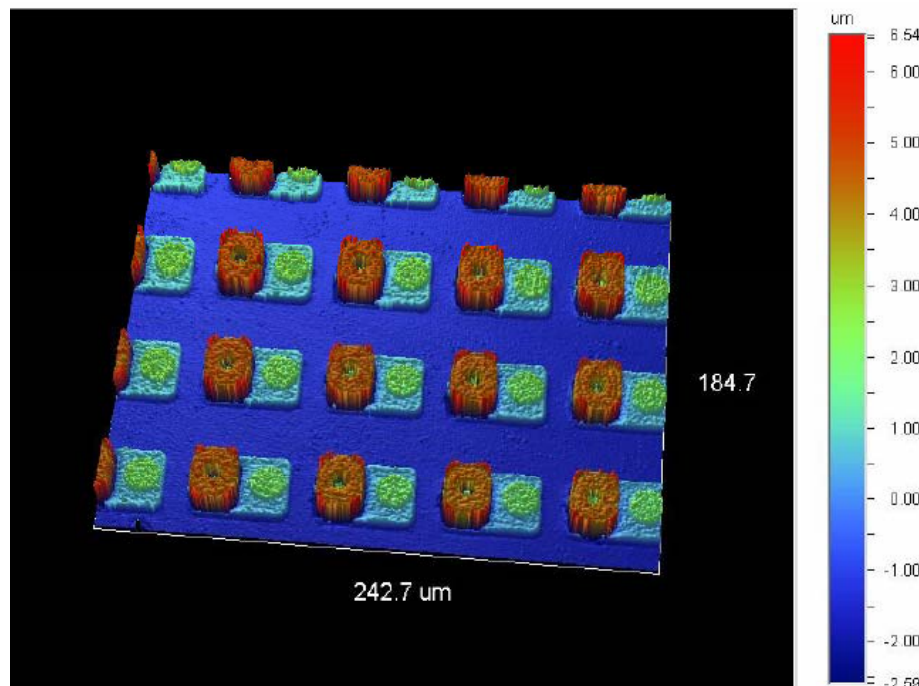


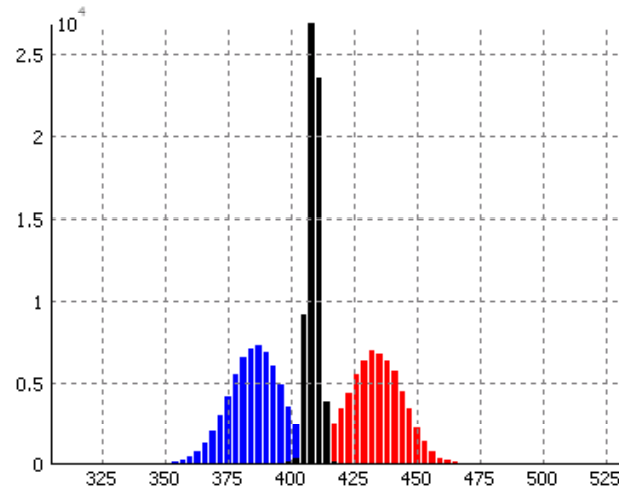
Image: VTT Finland



# MediPix

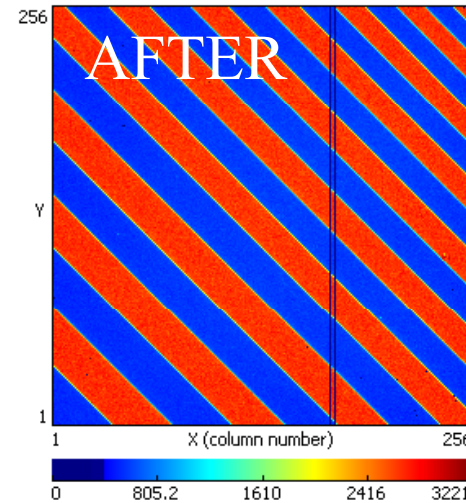
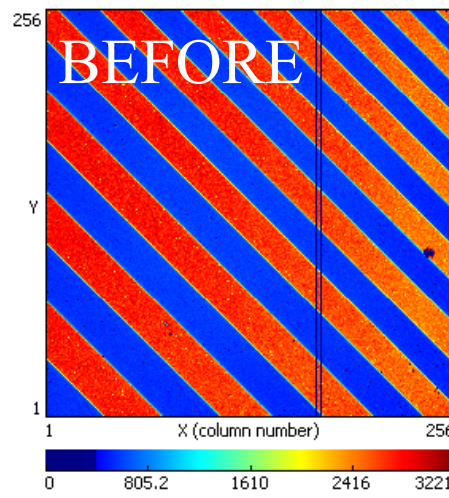
- 2<sup>nd</sup> grade sensors – two dead columns
- Unbonded pixels at the edge of two devices

Threshold  
Correction  
of each pixel



Noise Distribution  
Low Threshold All  
High Threshold All  
Individual Correction

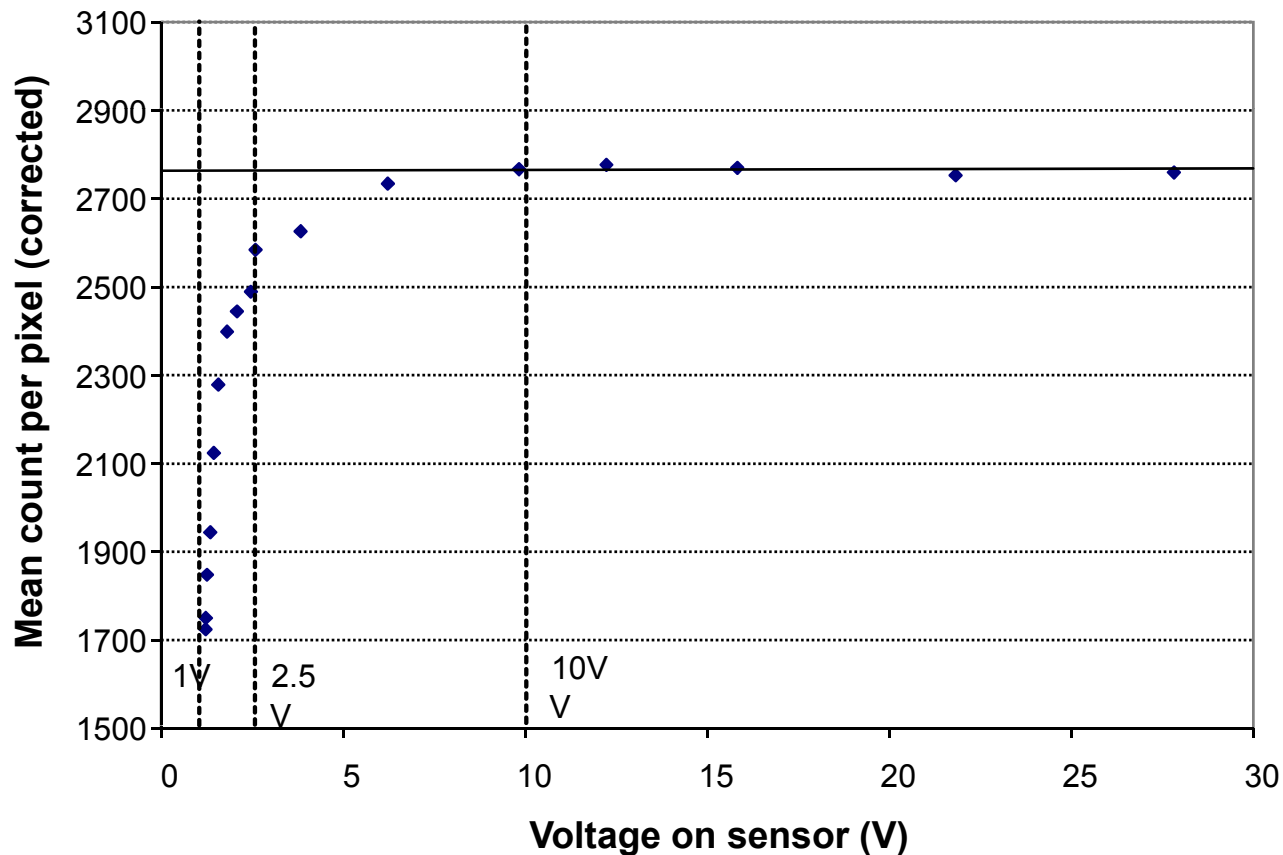
Flat Field  
Correction



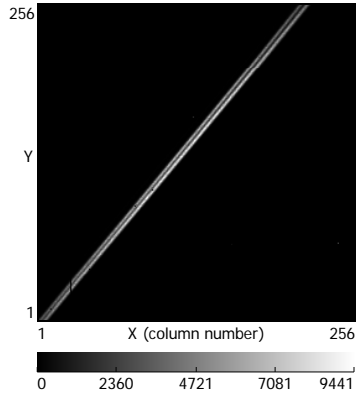
# Pixel Count Rate versus Voltage

- Confirm IV,CV result for pad, strip devices

## 3D - Bias scan with X-ray tube

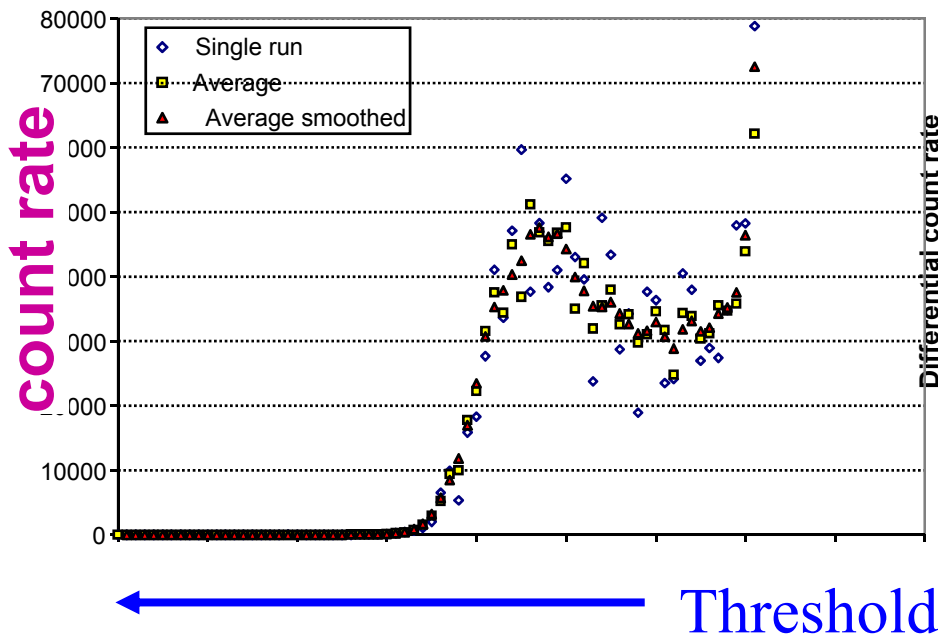


# Monochromatic X-ray

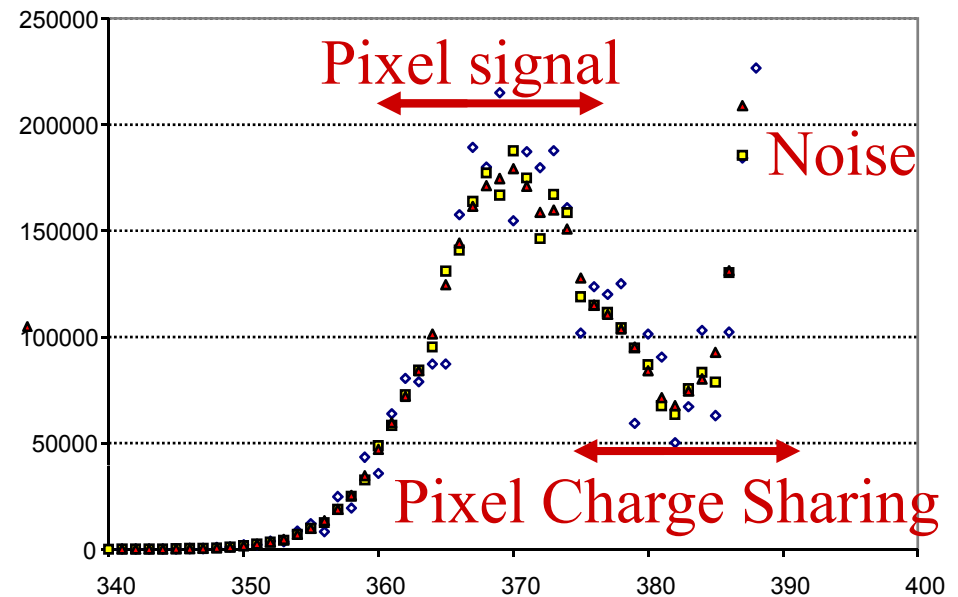


- 8 keV X-ray
- Planar Medipix/ 3D Medipix
- Compatible Signal
- Reduced Charge-sharing

Planar



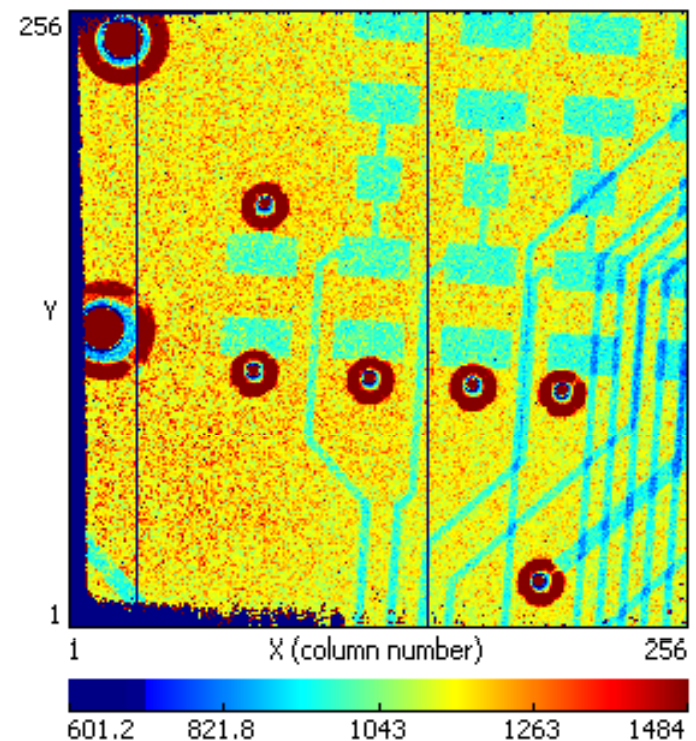
3D



# Summary

- Pad, Strip & Pixel Detectors Tested
  - Lateral depletion 2.3V
  - Strip MIP show 15:1 Signal:Noise
  - Reduced Charge sharing
- CV,IV after irradiation
  - Depletion expected  $\sim 50V$
  - To test at low temp
  - To do MIP tests
- Future Work
  - Production CNM, ICEMOS
  - Testbeam at Diamond
  - Testbeam at FNAL
    - (LHCb VELO)

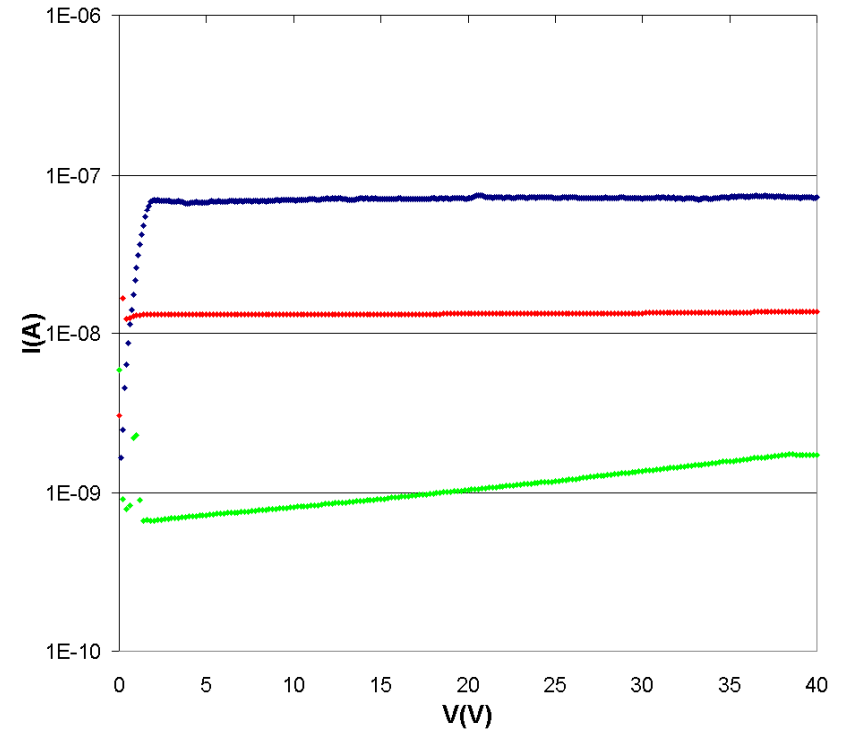
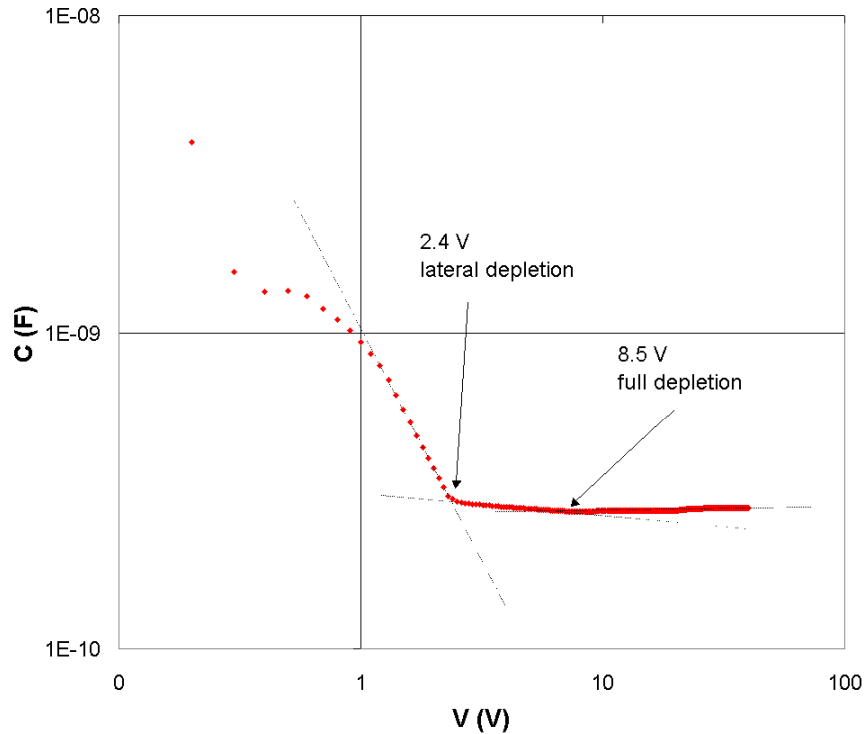
3D Medipix image of a PCB



# Backup



# Pre-irradiation results in pad detectors



- Guard ring and central diode at 0V, backside biased,  $T = 21^\circ\text{C}$
- Lateral depletion at **2.4 V** (pitch  $55 \mu\text{m}$ ), full depletion at  **$\sim 8.5$  V**
- Current per hole **0.1–10 pA**
- Two detectors tested to 40 V, one to 200 V, without signs of **breakdown**

# Charge collection results CNM3D strip

